# Data-Driven Nonparametric Hypothesis Testing

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### **Problem formulation**

There are in total M distinct discrete distributions  $p_1, ..., p_M$  and a testing sequence y, which consists of *n* i.i.d. samples generated by one of the *M* distributions.

- Which is the distribution that generates the test sequence?
- $p_i$ 's for  $i > M_1$  are unknown;
- for an unknown  $p_i$ , a training sequence  $t_i$  is available.

# **Review of Existing Work**

## Main Result(continued)

•  $C(\cdot, \cdot)$  denotes the Chernoff information given by

$$C(p,q) = \max_{\lambda \in [0,1]} -\log\Big(\sum_{y \in \mathcal{Y}} p(y)^{\lambda} q(y)^{1-\lambda}\Big).$$
(5)

•  $\beta$  denotes the ratio between the lengths of training and testing sequences,  $\beta = \lim_{n \to \infty} \frac{\overline{n}}{n}$ .

#### Corollary.

1. If  $\beta > 0$ , test **(T)** is *exponentially consistent*. Especially, if  $\beta \to \infty$ , the error exponent goes to  $\min_{\{i,j:i\neq j\}} C(p_i, p_j)$ , which is optimal.

For parametric model, to make sequence detection between two distribution  $p_1$  and  $p_2$ , the optimal test is the likelihood ratio test (LRT), and the optimal error exponent is the Chernoff information  $C(p_1, p_2)$ . [1]

For universal outlier hypothesis testing, the error exponent of GLRT is determined by the Bhattacharyya distance between the typical and outlier distributions. [2]

### Testing

#### Test 1.

$$\sigma(\boldsymbol{y}) = \arg\min_{i} \left\{ \begin{array}{ll} D(\boldsymbol{\gamma}(\boldsymbol{y}) || \boldsymbol{p}_{i}), & \text{if } i \leq M_{1} \\ D(\boldsymbol{\gamma}(\boldsymbol{y}) || \boldsymbol{\gamma}(\boldsymbol{t}_{i})), & \text{if } i > M_{1} \end{array} \right\}.$$

•  $\gamma(y)$  denotes the empirical distribution of y given by

$$\gamma(y) \triangleq rac{ ext{number of samples } y ext{ in } y}{ ext{length of } y}.$$

•  $D(\cdot || \cdot)$  denotes the KL divergence given by

$$D(p||q) = \sum_{y \in \mathcal{Y}} p(y) \log \frac{p(y)}{q(y)}.$$

2. If  $\beta = 0$  and  $M_1 < M$ , the test **(T)** is not exponentially consistent.

# **Computation of Error Exponent**

#### • Approximation of error exponent (2)

 $G(q, q_j) = D(q||p_j) + \beta D(q_j||p_j) + l(D(q||q_j) - D(q||p_i)),$ min q,qj∈∆

### where

 $(\mathsf{T})$ 

(1)

(2)

(3)

(4)

 $l(x) = \begin{cases} 0, & x \ge 0\\ \frac{1}{2}\mu x^2, & x < 0 \end{cases}$ 

then update

$$q_{j}^{(k+1)} = \mathcal{P}_{\Delta}[q_{j}^{(k)} - s\nabla G_{q_{j}}(q^{(k)}, q_{j}^{(k)})]$$
$$q^{(k+1)} = \mathcal{P}_{\Delta}[q^{(k)} - s\nabla G_{q}(q^{(k)}, q_{j}^{(k)})].$$

#### • For error exponent (3)

$$q_{j}^{(k+1)} = \mathcal{P}_{\Delta}[q_{j}^{(k)} - s\nabla F_{q_{j}}(q_{j}^{(k)}, \lambda^{(k)})]$$
  
$$\lambda^{(k+1)} = \mathcal{P}_{[0,1]}[\lambda^{(k)} + s\nabla F_{\lambda}(q_{j}^{(k+1)}, \lambda^{(k)})].$$

(6)

(7)

(8)

(9)

(10)

(11)

### Main Result

#### Theorem 1.

Apply test (T) to the nonparametric multiple hypothesis testing problem. The error exponent of the maximum error probability is given by

 $\min_{\substack{i,j:i\neq j}} e_{i,j},$ 

where  $e_{i,j}$  is given as follows. • For  $i \leq M_1$  and  $j \leq M_1$ ,  $e_{i,j} = C(p_i, p_j)$ ; • For  $i \leq M_1$  and  $j > M_1$ ,

$$e_{i,j} = \min_{\substack{q,q_j \in \Delta \\ s.t.}} D(q||p_j) + \beta D(q_j||p_j)$$

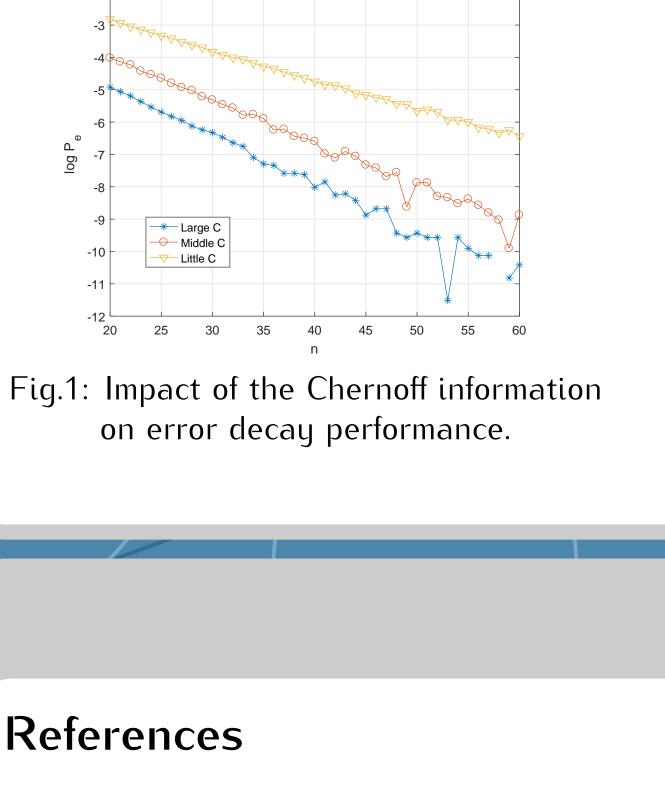
where  $\Delta = \{q : \sum_{y \in \mathcal{Y}} q(y) = 1, 0 \leq q(y) \leq 1\};$ • For  $i > M_1$  and  $j \leq M_1$ ,

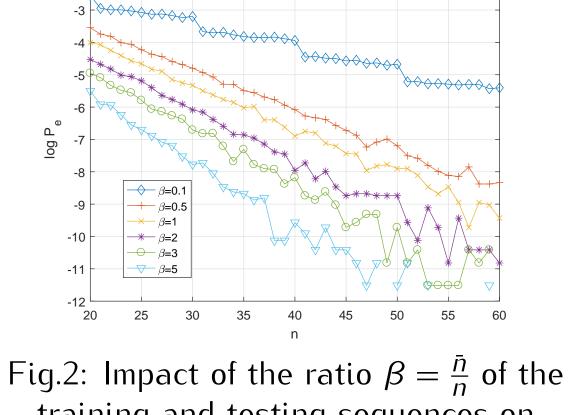
$$e_{i,j} = \min_{q_i \in \Delta} \quad C(q_i, p_j) + \beta D(q_i || p_i);$$

• For  $i > M_1$  and  $j > M_1$ ,

$$e_{i,j} = \min_{\substack{q,q_i,q_j \in \Delta \\ s.t.}} D(q||p_j) + \beta D(q_i||p_i) + \beta D(q_j||p_j)$$

## **Numerical Experiment**





training and testing sequences on error decay performance.

### References

[1] T. M. Cover and J. A. Thomas. *Elements of Information Theory*. John Wiley & Sons, 2012. [2] Y. Li, S. Nitinawarat, and V. V. Veeravalli. Universal outlier hypothesis testing. IEEE Transactions on Information Theory, 60(7):4066–4082, Apr. 2014.

